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•	Single-Chip RS-232 Interface for an External Modem or Other Computer Peripheral Serial Port	DB, DW, N, OR PW PACKAG (TOP VIEW)			
•	Designed to Transmit and Receive 4-μs	V _{CC} [] 1	20 V _{DD}		
	Pulses (Equivalent to 256 kbit/s)	DA1 [] 2	19 DY1		
•	Wide Driver Supply-Voltage Range: 4.75 V to 15 V	DA2 [] 3 DA3 [] 4 RV1 [] 5	18 DY2 17 DY3 16 RA1		
•	Driver Output Slew Rates Are Controlled	RY2 [] 6	15] RA2		
	Internally to 30 V/μs Maximum	DA4 [] 7	14] DY4		
•	Receiver Input Hysteresis 1000 mV	RY3 [] 8	13 RA3		
	Typical	DA5 [] 9	12 DY5		
•	RS-232 Bus-Pin ESD Protection Exceeds 15 kV Using Human-Body Model (HBM)	GND [10	11 V _{SS}		

- Five Drivers and Three Receivers Meet or Exceed the Requirements of TIA/EIA-232-F and ITU v.28 Standards
- Complements the SN75LP1185
- Designed to Replace the Industry-Standard SN75196 With the Same Flow-Through Pinout
- Package Options Include Plastic Small Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Dual-in-Line (N) Packages

description

The SN75LP196 is a low-power bipolar device containing five drivers and three receivers, with 15 kV of ESD protection on the bus pins with respect to each other. Bus pins are defined as those pins that tie directly to the serial-port connector, including GND. The pinout matches the flow-through design of the industry-standard SN75196 and allows easy interconnection of the UART and serial-port connector of the IBM PC/AT and compatibles. This device provides a rugged, low-cost solution for this function with the combination of bipolar processing and 15-kV ESD protection.

The SN75LP196 has internal slew-rate control to provide a maximum rate of change in the output signal of 30 V/ μ s. The driver output swing is clamped nominally at \pm 6 V to enable the higher data rates associated with this device and to reduce EMI emissions. Even though the driver outputs are clamped, they can handle voltages up to \pm 15 V without damage. All the logic inputs can accept 3.3-V or 5-V input signals.

The SN75LP196 complies with the requirements of the TIA/EIA-232-F and the ITU v.28 standards. These standards are for data interchange between a host computer and peripheral at signaling rates up to 20 kbit/s. The switching speeds of the SN75LP196 support rates up to 256 kbit/s with lower capacitive loads (shorter cables).

The SN75LP196 is characterized for operation from 0°C to 70°C.



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Function Tables

DRIVER							
INPUT DA	OUTPUT DY						
Н	L						
L	н						
Open	L						

RECEIVER

INPUT RA	OUTPUT RY
Н	L
L	Н
Open	Н

logic diagram (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Positive supply-voltage range (see Note 1): Vcc	
V _{DD} (see No	ote 1)
Negative supply-voltage range, V _{SS} (see Note 1)	
Input-voltage range, VI: Receiver (RA)	\ldots —30 V to 30 V
Driver (DA)	
Output-voltage range, V _O : Receiver (RY)	\ldots –0.5 V to 6 V
Driver (DY)	\ldots –15 V to 15 V
Electrostatic discharge: Bus pins (human-body model) (s	see Note 2) Class 3, A: 15 kV
All pins (human-body model) (se	ee Note 2) Class 3, A: 5 kV
All pins (machine model)	
Package thermal impedance, θ_{JA} (see Notes 3 and 4): D	DB package 115°C/W
Γ	DW package 97°C/W
١	N package 67°C/W
F	PW package 128°C/W
Lead temperature 1,6 mm (1/16 inch) from case for 10 se	econds 260°C
Storage temperature range, T _{stg}	65°C to 150°C

⁺ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to network ground terminal, unless otherwise noted.

- 2. Per MIL-STD-883 Method 3015.7
- 3. Maximum power dissipation is a function of $T_J(max)$, θ_{JA} , and T_A . The maximum allowable power dissipation at any allowable ambient temperature is $P_D = (T_J(max) T_A)/\theta_{JA}$. Operating at the absolute maximum T_J of 150°C can impact reliability.

4. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

			MIN	NOM	MAX	UNIT
Vcc	Supply voltage (see Note 5)		4.75	5	5.25	V
V _{DD}	Supply voltage (see Note 6)		9	12	15	V
VSS	Supply voltage (see Note 6)		-9	-12	-15	V
VIH	High-level input voltage	DA	2			V
VIL	Low-level input voltage	DA			0.8	V
VI	Receiver input voltage	RA	-25		25	V
IOH	High-level output current	RY			-1	mA
IOL	Low-level output current	RY			2	mA
TA	Operating free-air temperature		0		70	°C

NOTES: 5. V_{CC} cannot be greater than V_{DD}.

6. The device operates down to V_{DD} = V_{CC} and |V_{SS}| = V_{CC}, but supply currents increase and other parameters may vary slightly from the data-sheet limits.



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supply currents over the recommended operating conditions (unless otherwise noted)

PARAMETER		MIN	TYP	MAX	UNIT	
		$V_{DD} = 9 V$, $V_{SS} = -9 V$			1000	
Supply current for VCC, ICC	No load.	$V_{DD} = 12 \text{ V}, V_{SS} = -12 \text{ V}$			1000	μΑ
Supply current for Van Jan	All inputs at	$V_{DD} = 9 V$, $V_{SS} = -9 V$			800	
Supply current for VDD, IDD	minimum V _{OH} or	$V_{DD} = 12 \text{ V}, V_{SS} = -12 \text{ V}$			800	μΑ
	maximum vOL	$V_{DD} = 9 V$, $V_{SS} = -9 V$			-800	
Supply current for VSS, ISS		$V_{DD} = 12 \text{ V}, V_{SS} = -12 \text{ V}$			-800	μΑ

driver electrical characteristics over the recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
Vou	High lovel output veltage	$V_{IL} = 0.8 V,$	V _{DD} = 9 V,	$V_{SS} = -9 V,$	See Note 7	5	5.8	6.6	V
	See Figure 1	V _{DD} = 12 V,	$V_{SS} = -12 V,$	See Note 8	5	5.8	6.6	v	
Ve		$V_{IH} = 2 V$, $P_{IH} = 2 kO$	V _{DD} = 9 V,	$V_{SS} = -9 V,$	See Note 7	-5	-5.8	-6.9	V
VOL	Low-level output voltage	$R_{L} = 3 R_{22}$, See Figure 1	V _{DD} = 12 V,	$V_{SS} = -12 V,$	See Note 8	-5	-5.8	-6.9	V
Ιн	High-level input current	VI at V _{CC}	VI at V _{CC}				1	μA	
ЦĽ	Low-level input current	V _I at GND				-1	μA		
IOS(H)	Short-circuit high-level output current	$V_{O} = GND \text{ or } V_{SS}$	9	See Figure 2 a	and Note 9		-30	-55	mA
IOS(L)	Short-circuit low-level output current	$V_{O} = GND \text{ or } V_{DD},$ See Figure 2 and Note 9			30	55	mA		
r _o	Output resistance	$V_{DD} = V_{SS} = V_{CC}$	$V_{DD} = V_{SS} = V_{CC} = 0,$ $V_O = -2 \vee \text{to } 2 \vee$		300			Ω	

NOTES: 7. Minimum RS-232 driver output voltages are not attained with \pm 5-V supplies. With V_{DD} less than V_{CC} + 2 V, the supply currents may increase. For RS-232 compliant output swings and minimum power consumption, V_{DD} \ge V_{CC} + 2 V.

Maximum output swing is nominally clamped at ±6 V to enable the higher data rates associated with this device and to reduce EMI
emissions. The driver outputs may slightly exceed the maximum output voltage over the full V_{CC} and temperature ranges.

9. Not more than one output should be shorted at one time.



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	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT			
^t PHL	Propagation delay time, high- to low-level output	$R_L = 3 k\Omega \text{ to } 7 k\Omega, C$	$R_L = 3 \text{ k}\Omega$ to 7 k Ω , $C_L = 15 \text{ pF}$, See Figure 1			1600	ns			
^t PLH	Propagation delay time, low- to high-level output	$R_L = 3 k\Omega$ to 7 k Ω , C	$R_L = 3 k\Omega$ to 7 kΩ, $C_L = 15 pF$, See Figure 1			1600	ns			
	$\label{eq:constraint} \begin{tabular}{lllllllllllllllllllllllllllllllllll$	Using V _{TR} = 10%-to-90% transition region, Driver speed = 250 kbit/s, C_L = 15 pF	375		2240					
^t TLH		$V_{SS} = -12 V,$ $R_{L} = 3 k\Omega \text{ to } 7 k\Omega,$ See Figure 1 and Note 10	Using $V_{TR} = \pm 3$ V transition region, Driver speed = 250 kbit/s, C _L = 15 pF	200		1500	ns			
			Using V _{TR} = \pm 3 V transition region, Driver speed = 125 kbit/s, C _L = 2500 pF			2750				
		$V_{CC} = 5 V,$ $V_{DD} = 12 V.$	Using V _{TR} = 10%-to-90% transition region, Driver speed = 250 kbit/s, C_L = 15 pF	375		2240				
t _{THL}	Transition time, high- to low-level output See I Note	$V_{SS} = -12 V,$ $R_{L} = 3 k\Omega \text{ to } 7 k\Omega,$ See Figure 1 and Note 10	Using V _{TR} = \pm 3 V transition region, Driver speed = 250 kbit/s, C _L = 15 pF	200		1500	ns			
			Using V _{TR} = \pm 3 V transition region, Driver speed = 125 kbit/s, C _L = 2500 pF			2750				
SR	Output slew rate	$V_{CC} = 5 V,$ $V_{DD} = 12 V,$ $V_{SS} = -12 V,$	Using $V_{TR} = \pm 3$ V transition region, Driver speed = 0 to 250 kbit/s, C _L = 15 pF	4	20	30	V/μs			

driver switching characteristics over operating free-air temperature range (unless otherwise noted)

NOTE 10: Maximum output swing is limited to ±6 V to enable the higher data rates associated with this device and to reduce EMI emissions.

receiver electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST	CONDITIONS	MIN	TYP	MAX	UNIT
V _{IT+}	Positive-going input threshold voltage	See Figure 3		1.6	2	2.55	V
V _{IT} -	Negative-going input threshold voltage	See Figure 3		0.6	1	1.45	V
VHYS	Input hysteresis, VIT+ VIT–	See Figure 3		750	1000		mV
Vон	High-level output voltage	$I_{OH} = -1 \text{ mA}$		2.5	3.9		V
VOL	Low-level output voltage	I _{OL} = 2 mA			0.33	0.5	V
	Lich lough input ourrent	V _I = 3 V		0.43	0.6	1	A
I IH	High-level input current	V _I = 25 V		3.6	5.1	8.3	ША
1		V _I = 3 V		-0.43	-0.6	-1	~ ^
L IIL	Low-level input current	V _I = 25 V		-3.6	-5.1	-8.3	ША
IOS(H)	Short-circuit high-level output current	$V_{O} = 0,$	See Figure 5 and Note 9			-20	mA
IOS(L)	Short-circuit low-level output current	$V_{O} = V_{CC},$	See Figure 5 and Note 9			20	mA
R _{IN}	Input resistance	$V_I = \pm 3 V \text{ to } \pm 25 V$		3	5	7	kΩ

NOTE 9: Not more than one output should be shorted at one time.



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receiver switching characteristics over operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 4)

	PARAMETER	MIN	TYP	MAX	UNIT
^t PHL	Propagation delay time, high- to low-level output		400	900	2
^t PLH	Propagation delay time, low- to high-level output		400	900	115
^t TLH	Transition time, low- to high-level output		200	450	50
^t THL	Transition time, high- to low-level output		200	400	115
^t sk(p)	Pulse skew tpLH - tpHL		200	425	ns

PARAMETER MEASUREMENT INFORMATION



NOTES: A. The pulse generator has the following characteristics: For C_L < 1000 pF: t_W = 4 μ s, PRR = 250 kbit/s, Z_O = 50 Ω , t_r = t_f < 50 ns. For C_L = 2500 pF: t_W = 8 μ s, PRR = 125 kbit/s, Z_O = 50 Ω , t_r = t_f < 50 ns. B. C_L includes probe and jig capacitance.

Figure 1. Driver Parameter Test Circuit and Waveform







Figure 3. Receiver V_{IT} Test



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PARAMETER MEASUREMENT INFORMATION



NOTES: A. The pulse generator has the following characteristics: $t_W = 4 \mu s$, PRR = 250 kbit/s, $Z_O = 50 \Omega$, $t_f = t_f < 50 ns$. B. CL includes probe and jig capacitance.

Figure 4. Receiver Parameter Test Circuit and Waveform



Figure 5. Receiver I_{OS} Test

APPLICATION INFORMATION

Diodes placed in series with the V_{DD} and V_{SS} leads protect the SN75LP196 in the fault condition in which the device outputs are shorted to \pm 15 V and the power supplies are at low voltage and provide low-impedance paths to ground (see Figure 6).



Figure 6. Power-Supply Protection to Meet Power-Off Fault Conditions of EIA/TIA-232-F



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